

Notice of References Cited	Application/Control No. 10/533,448		Applicant(s)/Patent Under Reexamination IKEYA ET AL.	
	Examiner WAE LOUIE		Art Unit 3661	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,856,628 A	08-1989	Momiyama, Fujio	192/3.58
*	B	US-5,456,643 A	10-1995	Yamamoto et al.	477/110
*	C	US-5,595,551 A	01-1997	Hedstrom et al.	477/109
*	D	US-5,866,809 A	02-1999	Soderman, Goran	73/114.15
*	E	US-6,035,252 A	03-2000	Dixon et al.	701/102
*	F	US-6,155,955 A	12-2000	Boss et al.	477/107
*	G	US-6,345,529 B1	02-2002	Eskilson, Anders	73/115.02
*	H	US-6,379,283 B1	04-2002	Cullen, Michael John	477/110
*	I	US-2002/0142885 A1	10-2002	Graf et al.	477/115
*	J	US-6,711,964 B2	03-2004	Ochi et al.	74/337
*	K	US-2006/0047395 A1	03-2006	Ikeya et al.	701/051
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.